Hybrid 8j128 Traveler

January 4, 2000

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J128 has die: 197-042 197-044 197-045 197-048 199-111 199-112 199-113 199-117

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j128 classification info. Created 13:50:55 12/22/99

Hybrid 8j128 quality: fair
Chip classification: fair fair good fair good fair good good
Bad channels (chip-channel): 0-59 1-59
Bad cells: none
Random bad capacitors (chip-cell-channel): 1-10-59 1-11-2 1-12-59
   1-16-59 1-23-58 1-23-59 1-23-67 1-24-58 1-24-59 1-25-58 1-25-59
   1-26-59 1-27-59 1-28-84 1-36-59 1-37-58 1-37-59 1-38-125 1-38-58
   1-38-59 1-4-59 1-6-59 1-8-59 3-44-56 5-21-84 5-8-84
Channels at pedestal needed for DCMS: 29.6 32.6 32.6 31.6 33.6 34.6 33.6 32.6
```

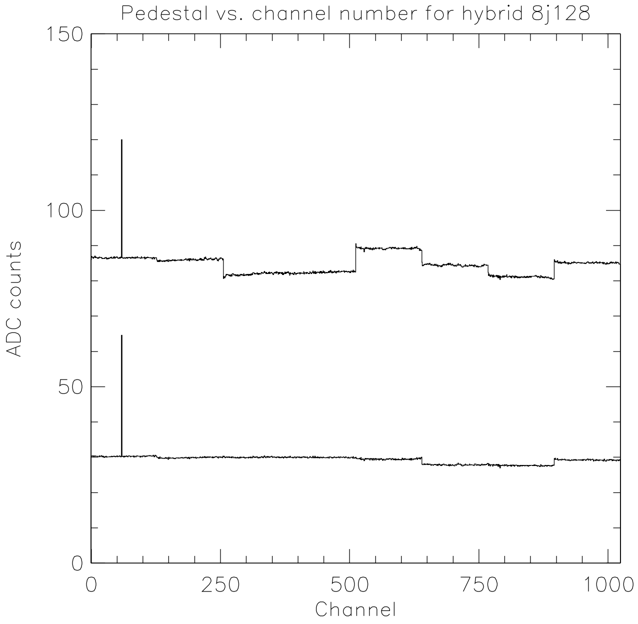
4 Comments

No comments.

5 Pedestal

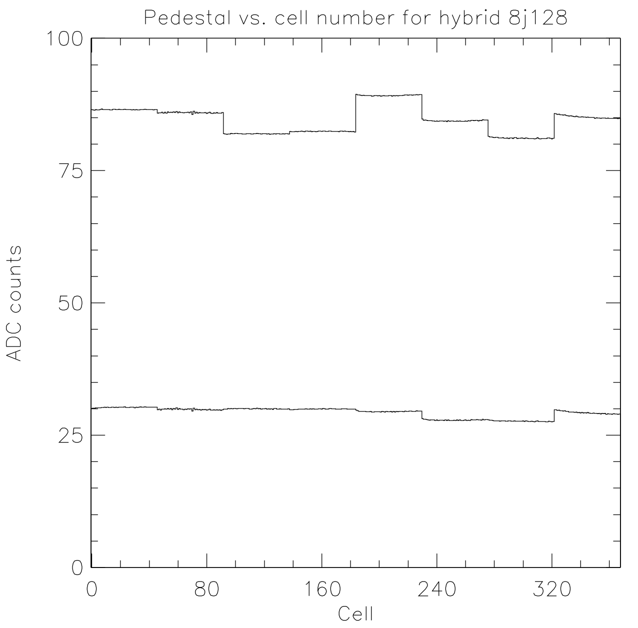
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

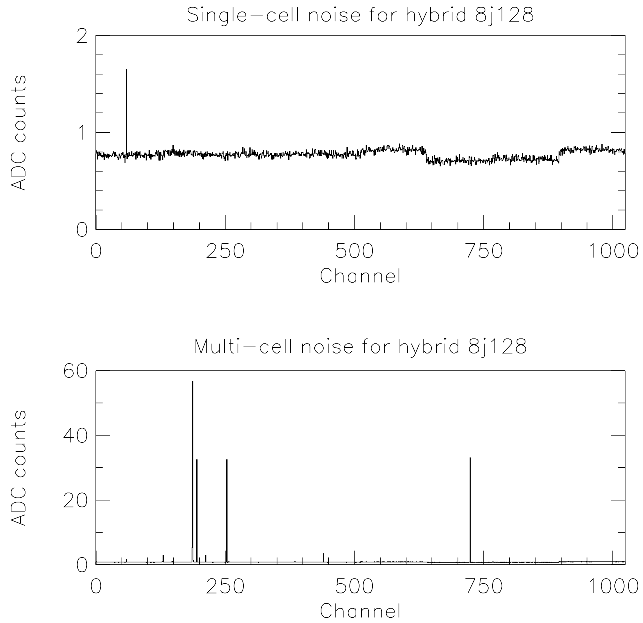
Pedestal vs. Pipeline Cell ID



6 Noise

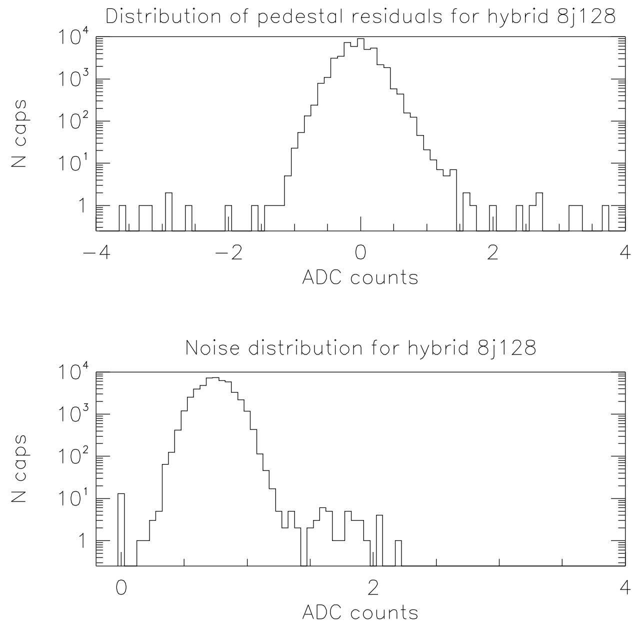
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise



The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in